

TRANSIENT STATE STUDY OF THE POLARIZATION PROPERTIES OF SIDEBAND RECOMBINATION EMISSIONS IN
GaN CRYSTALS

Qingcheng BAO*, Fengling ZHANG**, Shengmin PANG, Duolu LI, Nailiang TIAN and Xurong XU

Changchun Institute of Physics, Academic Sinica

In this paper, we report that the polarizabilities of near sideband recombination emission I_1 and I_3 in GaN crystal change quadratically with density of bound excitons.

1. INTRODUCTION

Exciton-exciton interaction has been an interesting problem for a long time. With the use of high power and short pulse Laser, intensity exciton system can be easily produced in crystals. This provides a basic experimental way to study interaction between excitons.

We analysed interaction between excitons and presented dispersion conception of exciton-exciton from dipole interaction^{1,2}.

We had reported the experimental result of polarization properties of sideband recombination emission in GaN crystal, with steady state spectra technique³, which give a proof for dispersion theory.

The transient polarization properties of near sideband recombination emission peak I_1 and I_3 in GaN crystal were experimentally studied with decay spectra technique and our results are reported in this paper. According to the result reported by Prof. Dai Rensong et al.⁴ that peak I_1 from recombination emission of BE^0 and I_3 from BEA^0 .

The results of transient spectra agree with our previous results of steady state experiments and provides an experiment proof for the dispersion theory of exciton-exciton interaction.

The excitation intensity in our experiments was $1.2 \times 10^5 \text{ W/cm}^2$, time precision was 10 ns and the temperature was $77 \pm 0.5 \text{ K}$.

2. EXPERIMENTAL SET-UP

An excimer laser EMG-102 was used as excitation light source. Its light quantum energy was 4.023 eV and the peak power can be changed from 0 to 10^8 W/cm^2 by a group of attenuators. The pulse width was 10 ns. The samples were put in the cryostat ESR-900. A polarizer was put before a double grating monochromator to pick out bound exciton emission polarized in parallel and perpendicular directions to the C-axis of GaN wafers respectively. After the monochromator, the light signal was amplified by a photomultiplier C31034 with cooling system. The amplified signal was then sent to Boxcar M-162, and then to an X-Y recorder.

* Dpt. of Chem., Univ. of Rochester, USA.

** Dpt. of Phys., Northern Jiaotong Univ., China.

3. EXPERIMENTAL RESULTS

We studied two kinds of samples, one was unintentionally doped GaN crystal, a typical sample was labeled by GaN-15#, the other was Zinc doped GaN crystal, a typical sample was labeled by GaN-16#. We recorded the decay spectra of I_{\parallel} and I_{\perp} , in two directions, that is, I_{\parallel} and I_{\perp} , where I_{\parallel} and I_{\perp} are the luminescence intensities parallel and perpendicular to C-axis of GaN crystal, respectively. The experimental results for GaN-15# and for GaN-16# are shown in Fig.1 and Fig.2 respectively.

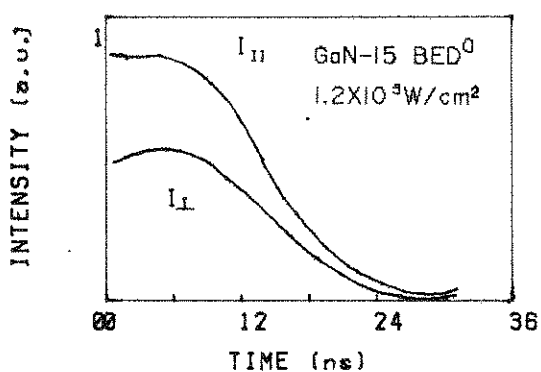


Fig.1 Decay spectra of GaN-15#

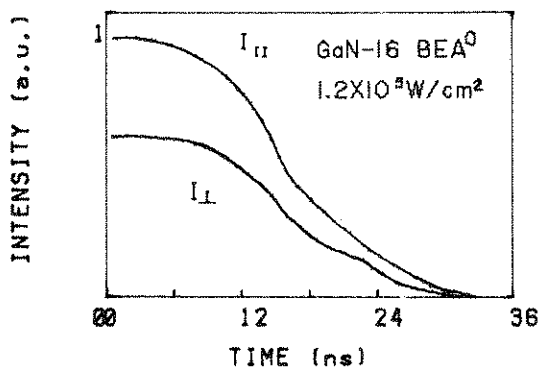


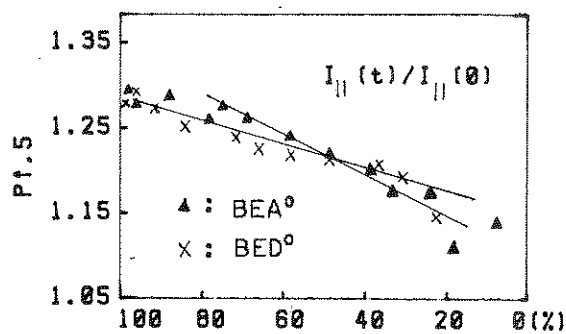
Fig.2 Decay spectra of GaN-16#

The polarizability of bound exciton emission P is defined as follows:

$$P(t) = I_{\parallel}(t)/I_{\perp}(t) \quad (1)$$

The following empirical formula $P(t) = (A + B \cdot b(t))^2$ was obtained from our experiment results.

The relation between $P^{1/5}(t)$ and b is shown in Fig.3.

Fig.3 The relation between $P^{1/5}(t)$ and b

4. CONCLUSIONS

These results supported our previous conclusions presented for exciton-exciton interaction.

REFERENCES

1. Bao Qingcheng, Dai Rensong and Xu Xurong, Abstract of "The Fifth Chinese Semiconductor Physics Conference" (1985) 230.
2. Bao Qingcheng, Zhang Fengling, Shi Ke, Dai Rensong and Xu Xurong, Solid State Commun., Vol.59, No.9 (1986) 599.
3. Zhang Fengling, Bao Qingcheng and Dai Rensong, Chinese J. Luminescence, Vol.7, No.2 (1986) 178.
4. R.Dai, et al., J.Phys.C., 15, (1982) 393.

ENHANCED REC

Kensuke OGAWA

Department of

Effect of de
liquid in Ge
recombination
 7.2×10^{10} or
for shallow

1. INTRODUCTION

Properties of
pure Ge crystal
Impurity effect
not clear. Lum
bound double e
or Zn-doped Ge.
acceptors. Re
level impurities

Under appli
a giant strain
In this paper,
e-h recombina
Recombination
Be- or Zn-dope
double accept
SCEHL.

2. EXPERIMENTAL

Dopant conc
and 1.0×10^{15}
 cm^{-3} and $2.1 \times$
 10^{13} cm^{-3} and
Ultra-high-pur
than 10^{11} cm^{-3}
Sample was

*Present address

0022-2313/88/\$03
(North-Holland Ph)